

PERRY JOHNSON LABORATORY ACCREDITATION, INC.

Certificate of Accreditation

Perry Johnson Laboratory Accreditation, Inc., has assessed the Laboratory of:

***CEMYR Instrumentos, S.A. de C.V.
Lomas de San Pedro # 211-A Col. Las Puentes 2do. Sector
San Nicolás de los Garza, Nuevo León 66460***

(Hereinafter called the Organization) and hereby declares that Organization is accredited in accordance with the recognized International Standard:

ISO/IEC 17025: 2005

This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (as outlined by the joint ISO-ILAC-IAF Communiqué dated January 2009):

Calibration of Measuring Instruments (As detailed in the supplement)

Such testing and/or calibration services shall only be offered at or from the address given above. This Accreditation is granted subject to the system rules governing the Accreditation referred to above, and the Organization hereby covenants with the Accreditation body's duty to observe and comply with the said rules.

For PJLA:

The validity of this certificate is mandated through ongoing surveillance.

Tracy Szerszen
President/Operations Manager

Perry Johnson Laboratory
Accreditation, Inc. (PJLA)
26555 Evergreen, Suite 1325
Southfield, Michigan 48076

Initial Accreditation Date:

March 30, 2008

Issue Date:

March 30, 2008

Revision Date:

February 23, 2009

Expiration Date:

March 29, 2010

Accreditation No.

60097

Certificate No.

L08-7-R1

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Certificate of Accreditation: Supplement

CEMYR Instrumentos, S.A. de C.V.
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Accreditation is granted to this facility to perform the following calibrations:

Optical

| MEASURED INSTRUMENT, QUANTITY OR GAUGE | RANGE (AND SPECIFICATION WHERE APPROPRIATE) | BEST MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (\pm) | REMARKS |
|---|---|---|---------|
| Reflectance Spectrocolorimeters Reflectance Spectrophotometers | 400 nm to 700 nm 0 % to 100 % reflectance (ρ) Color Values: CIE L*: 0 to 100 CIE a*: -40.0 to 40.0 CIE b*: -40.0 to 88 | L*: 0.21 a*: 0.08 b*: 0.12 | |
| Transmittance Spectrophotometers | τ : 10 % T to 50 % T | 0.06 % T at 10 % T 0.23 % T at 50 % T | |
| | λ : 241.1 nm to 641.1 nm | 0.14 nm | |
| Tristimulus Colorimeter | Color Values: CIE L*: 97.52 CIE a*: -0.02 CIE b*: 1.59 | L*: 0.30 a*: 0.1 b*: 0.15 | |

Mass, Force, and Weighing Devices

| MEASURED INSTRUMENT, QUANTITY OR GAUGE | RANGE (AND SPECIFICATION WHERE APPROPRIATE) | BEST MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (\pm) | REMARKS |
|---|---|---|---------|
| Scales and Balances | .1 kg to 100 kg | 0.003 kg | |

Dimensional

| MEASURED INSTRUMENT, QUANTITY OR GAUGE | RANGE (AND SPECIFICATION WHERE APPROPRIATE) | BEST MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (\pm) | REMARKS |
|---|---|---|---------|
| Thickness Gages | 10 μ m to 1 000 μ m | 1.5 μ m | |

1. Remarks: This column shall include pertinent information about the calibration of the Measured Instrument or parameter. The information should include the type of standards used and any pertinent information about the measurement method. This column is not to be used for commercial advertisement of laboratory services.